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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/658,510	09/08/2003	Ralph A. Carbone	10012439-2	1778
7590 12/22/2004			EXAMINER	
HEWLETT PACKARD COMPANY			RAEVIS, ROBERT R	
Intellectual Prog	perty Administration			
P. O. Box 272400 Fort Collins, CO 80527-2400			ART UNIT	PAPER NUMBER
			2856	

DATE MAILED: 12/22/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	10/658,510	CARBONE ET AL.			
Office Action Summary	Examiner	Art Unit			
	Robert R. Raevis	2856			
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period we Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	6(a). In no event, however, may a reply be tim within the statutory minimum of thirty (30) days ill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI	nely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).			
Status		•			
1) Responsive to communication(s) filed on					
2a) This action is FINAL . \sim 2b) This action is non-final.					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under E	x parte Quayle, 1935 C.D. 11, 45	3 O.G. 213.			
Disposition of Claims					
4) Claim(s) 1-23 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) Claim(s) is/are allowed. 6) Claim(s) 1.2.5-16.21-23 is/are rejected. 7) Claim(s) 3.4 and 17-20 is/are objected to. 8) Claim(s) are subject to restriction and/or					
Application Papers					
9) The specification is objected to by the Examiner					
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.					
Applicant may not request that any objection to the o					
Replacement drawing sheet(s) including the correcting 11) The oath or declaration is objected to by the Example 11.		• •			
Priority under 35 U.S.C. § 119					
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list of	have been received. have been received in Application ity documents have been received (PCT Rule 17.2(a)).	on No ed in this National Stage			
Attachment(s)	о п	(PTO 440)			
) U Notice of References Cited (PTO-892)) Notice of Draftsperson's Patent Drawing Review (PTO-948)	4) lnterview Summary Paper No(s)/Mail Da	te			
Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	5) Notice of Informal P 6) Other:	atent Application (PTO-152)			

DETAILED ACTION

Claims 1, 2, 5-8, 11, 13-16, 21 and 22 are rejected under 35 U.S.C. 102(a) as being anticipated by Applicant's Admission.

Applicant describes (pages 1-4) a method of sampling for a "presence" (col. 4, line 1) of fragile whisker-like metallic particulates, comprising: providing a "wet wipe" (p. 4, line 5) swatch capable of capturing and retaining the particulates; transporting the swatch to a suspect surface of a data center; extracting from the surface any particulates that may be present. The described method sometimes permits for determination of the form (geometry) of a zinc whisker, and sometimes even permits for a determination of zinc whisker length (geometry). (See page 4, lines 7-11, of Applicant's written description.)

As to claims 1, 11, 13, 15, 16, 21, the sampling takes place on tile surfaces of a data center, and thus the surfaces are such that particulates may be present.

Therefore, those suspect areas being sampled from are located as claimed.

As to claims 2, 15, 16, 21, the particulates being sampled adhere to the wet wipe.

As to claim 5, swatches are rubbed along a surface, requiring pressure.

As to claim 6, Applicant describes sampling from "a given area" (p.4, line 11) to determination "the concentration" (p. 4, line 11) of particulates, suggestive of determination of density.

As to claim 8, see p. 4, lines 6's "plastic bag" teaching.

As to claim 14, potential sample areas include the bottom of floor tiles, as they are "dragged across the top of each other" (p. 3, lines 21-22), necessarily causing particulates on bottom surfaces.

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As to claim 22, note that identification is carried out by "visual inspection" (p. 3, last line) in addition ("and/or", italics added, p. 3, last line) to the "wiping" (p. 3, last line).

Claims 7 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant's statement.

As to claim 7, it is known to relate particular sample results to the area sampled for subsequent addressing of any results, suggestive of recording.

As to claim 12, it would have been obvious to take more than one sample from different areas of interest to allow for a test for a greater region to allow for a more comprehensive test.

Claims 8 and 9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant's Statement as applied to claim 1 above, and further in view of Jezek.

As to claims 8 and 9, it would have been obvious to store any sample taken because Jezek teaches (col. 2, lines 22-24) use of a container to protect a sample after collection, suggestive of use of a container to protect any sample.

Claim 23 is rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant's Statement as applied to claim15 above, and further in view of Johnsson et al.

As to claim 23, it would have been obvious to employ a EDS analysis to the sampled material because Johnsson et al teach (col. 2, lines 40-50) application of EDS analysis to analyze whiskers.

Claim 10 is rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant's Statement as applied to claim 2 above, and further in view of Moos.

As to claim 10, Moos (col. 3, lines 11-27) teaches that surface samplers employ holders that permit for holding any "type of material" (co. 3, line 19) to allow for sampling of a "known Art Unit: 2856

sampler area" (col. 1, line 51) with a standard manner (i.e. "pressure" (col. 1, line 54)) to provide a standard sample for analysis.

Regarding Applicant's REMARKS, consider the following:

As to pages 9-10, Applicant's statement (p. 4, lines 5-11) clearly implies that it's known to try to use "wet wipe" swatch to determine if zinc is in the form of a whisker, and even to try to determine the length of the whisker. This would seem to suggest that the swatch is capable of capturing whisker like particulates, and extracting particulates from the surface in a manner enabling characterization as claimed.

As to p. 11, first full paragraph; the term "adhesive" is broader than that argued by Applicant. It would be a simple matter to place the Applicant's argued substance of his definition of "adhesive" in a claim.

As to p. 12, top paragraph; samples in a bag are protected from contamination.

As to p. 12, second paragraph; the specification expressly suggests the bottom of the floor tile as a suspect area (i.e. area of interest) for sampling.

As to p. 12, third paragraph; the specification expressly suggests that "visual inspection" is employed. Visual inspection involves seeing the sampled items, necessarily involving seeing their shapes.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Robert R. Raevis whose telephone number is 571-272-2204. The examiner can normally be reached on Monday to Friday from 6:30am to 4:00pm. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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